

**Notice of References Cited**

Application/Control No.

10/085,659

Applicant(s)/Patent Under  
Reexamination  
NISHI ET AL.

Examiner

BRIAN P. YENKE

Art Unit

2622

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Frankowski, "Real-time 3D Shape Measurement with Digital Strip Projection by Texas Instruments Micromirror Devices DMD", SPE Vol 3958 (2000), pp 90-105.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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